

2.5V SINGLE DATA RATE 1:5 CLOCK BUFFER TERABUFFER™ JR.

IDT5T9050 NRND

NOT RECOMMENDED FOR NEW DESIGNS

FEATURES:

- Optimized for 2.5V LVTTL
- Guaranteed Low Skew < 25ps (max)
- Very low duty cycle distortion < 300 (max)
- High speed propagation delay < 1.8ns. (max)
- Up to 200MHz operation
- Very low CMOS power levels
- · Hot insertable and over-voltage tolerant inputs
- 1:5 fanout buffer
- 2.5V VDD
- Available in TSSOP package
- NOT RECOMMENDED FOR NEW DESIGNS

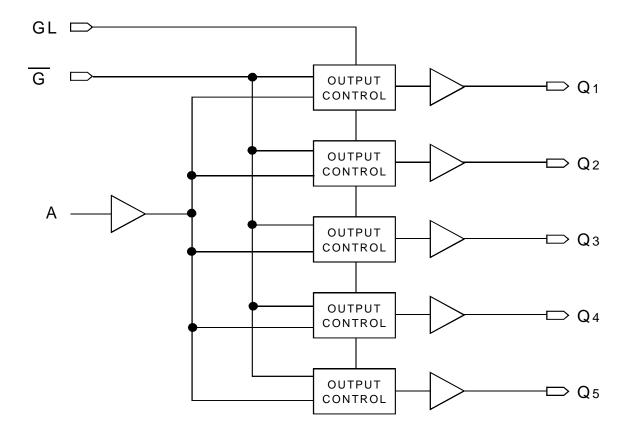
DESCRIPTION:

The IDT5T9050 2.5V single data rate (SDR) clock buffer is a single-ended input to five single-ended outputs buffer built on advanced metal CMOS technology. The SDR clock buffer fanout from a single input to five single-ended outputs reduces the loading on the preceding driver and provides an efficient clock distribution network. Multiple power and grounds reduce noise.

APPLICATIONS:

· Clock and signal distribution

FUNCTIONAL BLOCK DIAGRAM

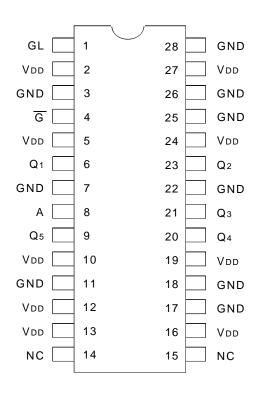


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INDUSTRIAL TEMPERATURE RANGE

MAY 2013

PIN CONFIGURATION



TSSOP TOP VIEW

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Description	Max	Unit
VDD	Power Supply Voltage	-0.5 to +3.6	٧
Vı	Input Voltage	-0.5 to +3.6	V
Vo	Output Voltage	-0.5 to V _{DD} +0.5	V
Tstg	Storage Temperature	-65 to +165	°C
TJ	Junction Temperature	150	°C

NOTE:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

CAPACITANCE⁽¹⁾ (TA = +25°C, F = 1.0MHz)

Symbol	Parameter	Min	Тур.	Max.	Unit
CIN	Input Capacitance	_	6	_	pF

NOTE:

1. This parameter is measured at characterization but not tested.

RECOMMENDED OPERATING RANGE

Symbol	Description	Min.	Тур.	Max.	Unit
TA	Ambient Operating Temperature	-40	+25	+85	°C
VDD	Internal Power Supply Voltage	2.3	2.5	2.7	V

PIN DESCRIPTION

Symbol	I/O	Туре	Description
Α	1	LVTTL	Clockinput
G	I	LVTTL	Gate control for Qn outputs. When \overline{G} is LOW, these outputs are enabled. When \overline{G} is HIGH, these outputs are asynchronously disabled to the level designated by $GL^{(1)}$.
GL		LVTTL	Specifies output disable level. If HIGH, the outputs disable HIGH. If LOW, the outputs disable LOW.
Qn	0	LVTTL	Clock outputs
VDD		PWR	Power supply for the device core, inputs, and outputs
GND		PWR	Power supply return for power

NOTE:

^{1.} Because the gate controls are asynchronous, runt pulses are possible. It is the user's responsibility to either time the gate control signals to minimize the possibility of runt pulses or be able to tolerate them in down stream circuitry.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE⁽¹⁾

Symbol	Parameter	Test Conditi	ons	Min.	Typ. ⁽⁴⁾	Max	Unit
Іін	Input HIGH Current	$V_{DD} = 2.7V$	$V_{I} = V_{DD}/GND$	_	ı	±5	μΑ
lıL	Input LOW Current	$V_{DD} = 2.7V$	$V_I = GND/V_{DD}$	1	ı	±5	
Vik	Clamp Diode Voltage	$V_{DD} = 2.3V$, $I_{IN} = -18n$	nA		- 0.7	- 1.2	V
Vin	DC Input Voltage			- 0.3		+3.6	V
ViH	DC Input HIGH ⁽²⁾			1.7		ı	V
VIL	DC Input LOW ⁽³⁾					0.7	V
Vон	Output HIGH Voltage	lон = -12mA		V _{DD} - 0.4		-	V
		Іон = -100μΑ		VDD - 0.1		-	V
Vol	Output LOW Voltage	lol = 12mA		_		0.4	V
		IoL = 100μA		_		0.1	V

NOTES:

- 1. See RECOMMENDED OPERATING RANGE table.
- 2. Voltage required to maintain a logic HIGH.
- 3. Voltage required to maintain a logic LOW.
- 4. Typical values are at $V_{DD} = 2.5V$, $+25^{\circ}C$ ambient.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾	Тур.	Max	Unit
IDDQ	Quiescent Vdd Power Supply Current	VDD = Max., Reference Clock = LOW	1	1.5	mA
		Outputs enabled, All outputs unloaded			
Iddd	Dynamic Vdd Power Supply	VDD = Max., CL = 0pF	100	150	μA/MHz
	Current per Output				
Ітот	Total Power Vdd Supply Current	VDD = 2.5V., Freference clock = 100MHz, CL = 15pF	50	65	mA
		VDD = 2.5V., FREFERENCE CLOCK = 200MHz, CL = 15pF	75	100	

NOTE:

1. The termination resistors are excluded from these measurements.

INPUT AC TEST CONDITIONS

Symbol	Parameter	Value	Units
ViH	Input HIGH Voltage	Vdd	V
VIL	Input LOW Voltage	0	V
Vтн	Input Timing Measurement Reference Level ⁽¹⁾	V _{DD} /2	V
tr, tr	Input Signal Edge Rate ⁽²⁾	2	V/ns

NOTES:

- 1. A nominal 1.25V timing measurement reference level is specified to allow constant, repeatable results in an automatic test equipment (ATE) environment.
- 2. The input signal edge rate of 2V/ns or greater is to be maintained in the 10% to 90% range of the input waveform.

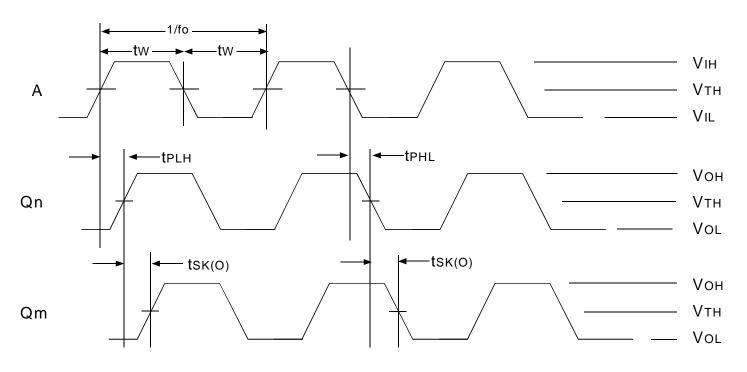
AC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE⁽⁴⁾

Symbol	Parameter	Min.	Тур.	Max	Unit
Skew Parameters	3	•			
tsk(o)	Same Device Output Pin-to-Pin Skew ⁽¹⁾	_	_	25	ps
tsk(p)	Pulse Skew ⁽²⁾	_	_	300	ps
tsk(pp)	Part-to-Part Skew ⁽³⁾	_	_	300	ps
Propagation Dela	ay _				
t PLH	Propagation Delay A to Qn	_	_	1.8	ns
t PHL					
tr	Output Rise Time (20% to 80%)	350	_	850	ps
t _F	Output Fall Time (20% to 80%)	350	_	850	ps
fo	Frequency Range		_	200	MHz
Output Gate Enak	ole/Disable Delay				
t PGE	Output Gate Enable to Qn	_	_	3.5	ns
t PGD	Output Gate Enable to Qn Driven to GL Designated Level	_	_	3	ns

NOTES:

- 1. Skew measured between all outputs under identical input and output transitions and load conditions on any one device.
- 2. Skew measured is the difference between propagation delay times tehl and tell of any output under identical input and output transitions and load conditions on any one device.
- 3. Skew measured is the magnitude of the difference in propagation times between any outputs of two devices, given identical transitions and load conditions at identical Vpb levels and temperature.
- 4. Guaranteed by design.

AC TIMING WAVEFORMS

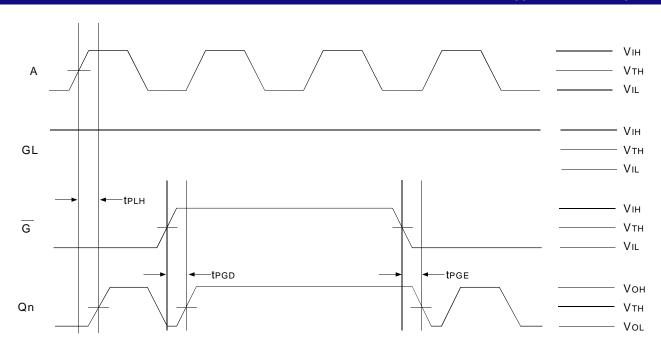


Propagation and Skew Waveforms

NOTE: Pulse Skew is calculated using the following expression:

$$tsk(P) = |tPHL - tPLH|$$

where tphl and tplh are measured on the controlled edges of any one output from rising and falling edges of a single pulse. Please note that the tphl and tplh shown are not valid measurements for this calculation because they are not taken from the same pulse.

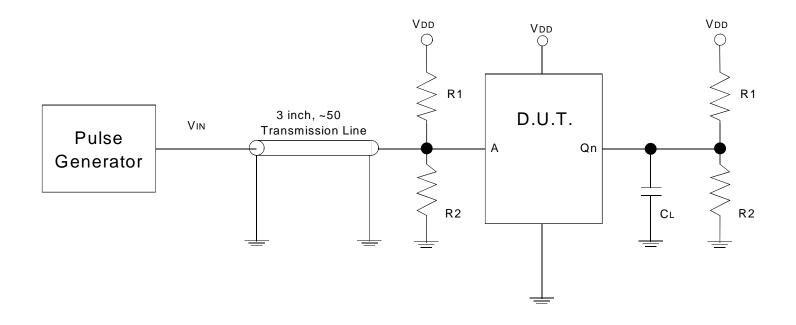


Gate Disable/Enable Showing Runt Pulse Generation

NOTE:

As shown, it is possible to generate runt pulses on gate disable and enable of the outputs. It is the user's responsibility to time their \overline{G} signal to avoid this problem.

TEST CIRCUIT AND CONDITIONS

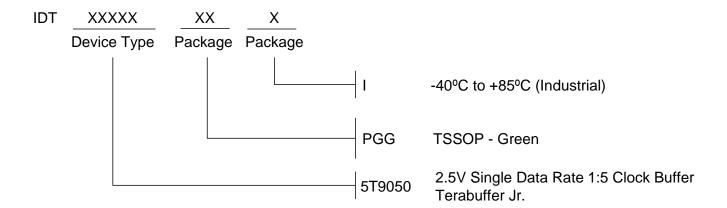


Test Circuit for Input/Output

INPUT/OUTPUT TEST CONDITIONS

Symbol	$V_{DD} = 2.5V \pm 0.2V$	Unit
V TH	V _{DD} / 2	V
R1	100	Ω
R2	100	Ω
CL	15	pF

ORDERING INFORMATION



REVISION HISTORY

Rev	Table	Page	Discription of Change	Date
А		1	NRND - Not Recommended for New Designs	5/5/13

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